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(12) **United States Design Patent**
Okajima et al.

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(54) **SUPPORTING COLUMN OF INSULATION UNIT FOR SEMICONDUCTOR MANUFACTURING APPARATUS**

(71) Applicant: **KOKUSAI ELECTRIC CORPORATION**, Tokyo (JP)

(72) Inventors: **Yusaku Okajima**, Toyama (JP); **Shuhei Saïdo**, Toyama (JP); **Hidenari Yoshida**, Toyama (JP)

(73) Assignee: **KOKUSAI ELECTRIC CORPORATION**, Tokyo (JP)

(**) Term: **15 Years**

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(30) **Foreign Application Priority Data**

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(51) **LOC (13) Cl.** **13-03**

(52) **U.S. Cl.**
USPC **D13/184**

(58) **Field of Classification Search**
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D13/151, 182, 184
CPC C30B 25/14; H01L 21/67017; C23C
16/4412; C23C 16/45578; C23C 16/44;
C23C 16/455
See application file for complete search history.

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Primary Examiner — Keli L Hill

Assistant Examiner — Harold E Blackwell, II

(74) *Attorney, Agent, or Firm* — Fitch, Even, Tabin & Flannery, LLP

(57) **CLAIM**

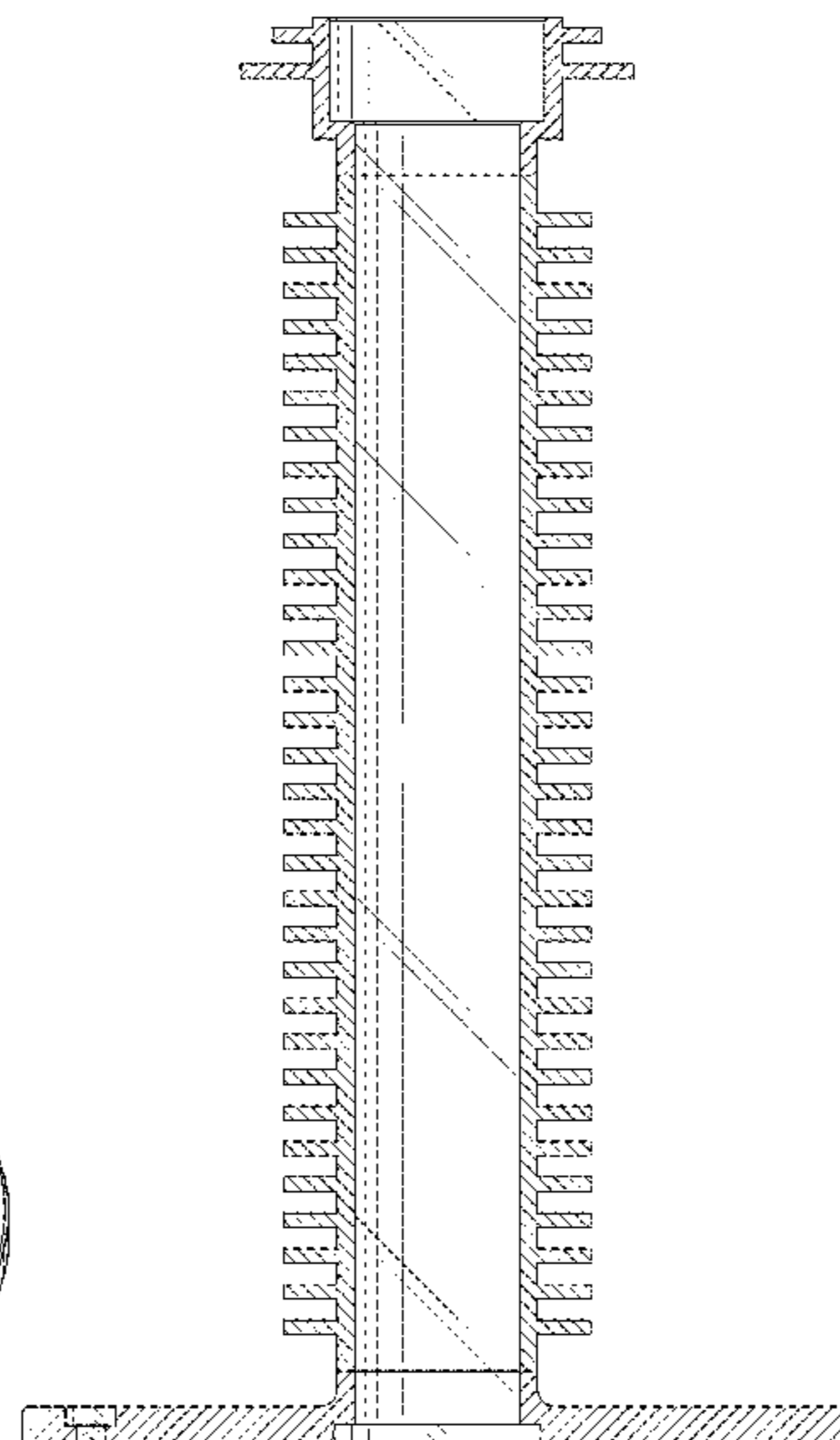
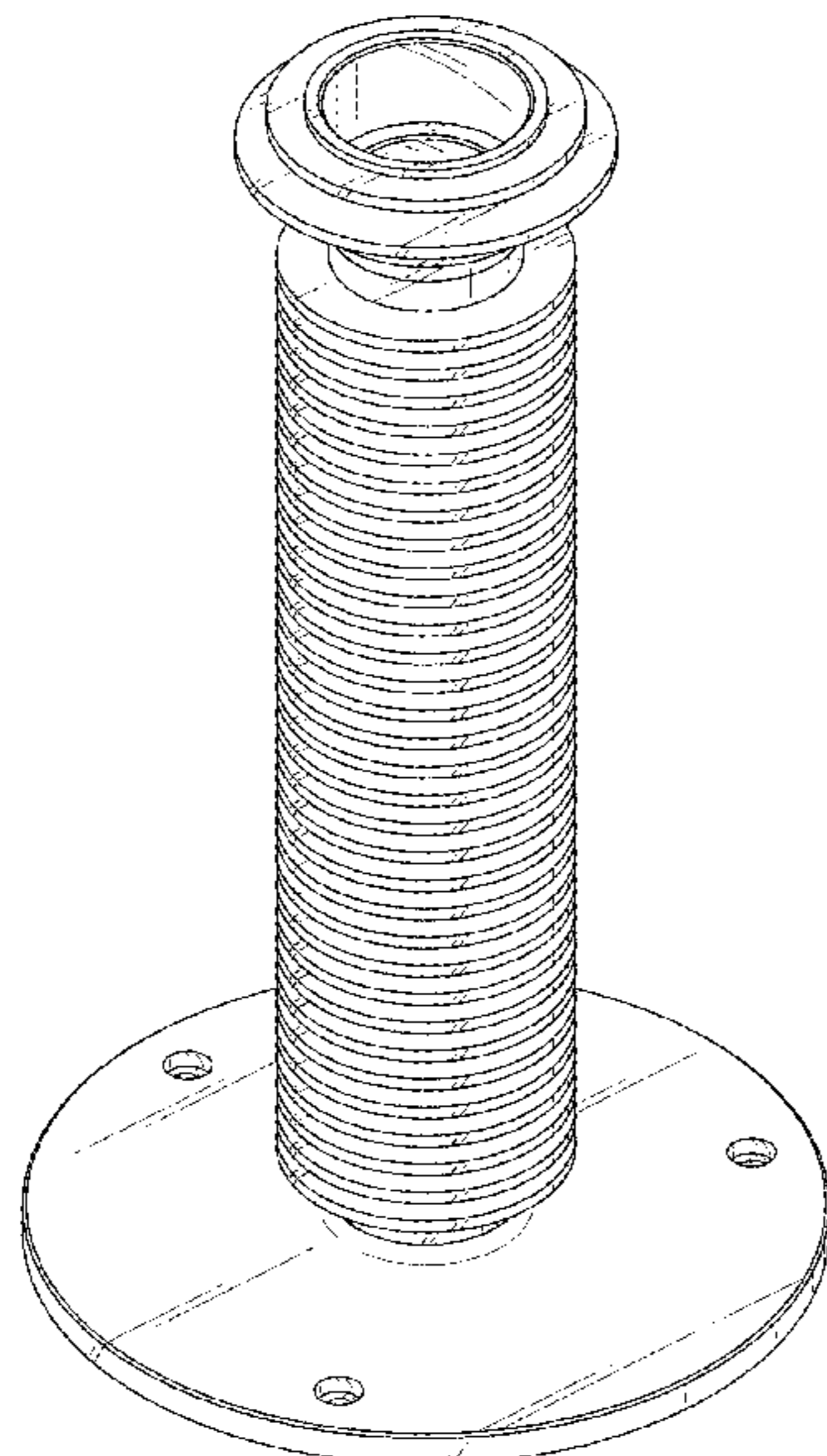
The ornamental design for a supporting column of insulation unit for semiconductor manufacturing apparatus, as shown (and described).

DESCRIPTION

FIG. 1 is a front, top and right side perspective view of a supporting column of insulation unit for semiconductor manufacturing apparatus showing our new design; FIG. 2 is a front elevational view thereof; FIG. 3 is a rear elevational view thereof; FIG. 4 is a right side elevational view thereof; FIG. 5 is a left side elevational view thereof; FIG. 6 is a top plan view thereof; FIG. 7 is a bottom plan view thereof; and, FIG. 8 is a cross-sectional view take along line 8-8 in FIG. 2.

The dot-dash broken lines FIG. 2 are for reference purposes only; the broken lines form no part of the claimed design.

1 Claim, 7 Drawing Sheets



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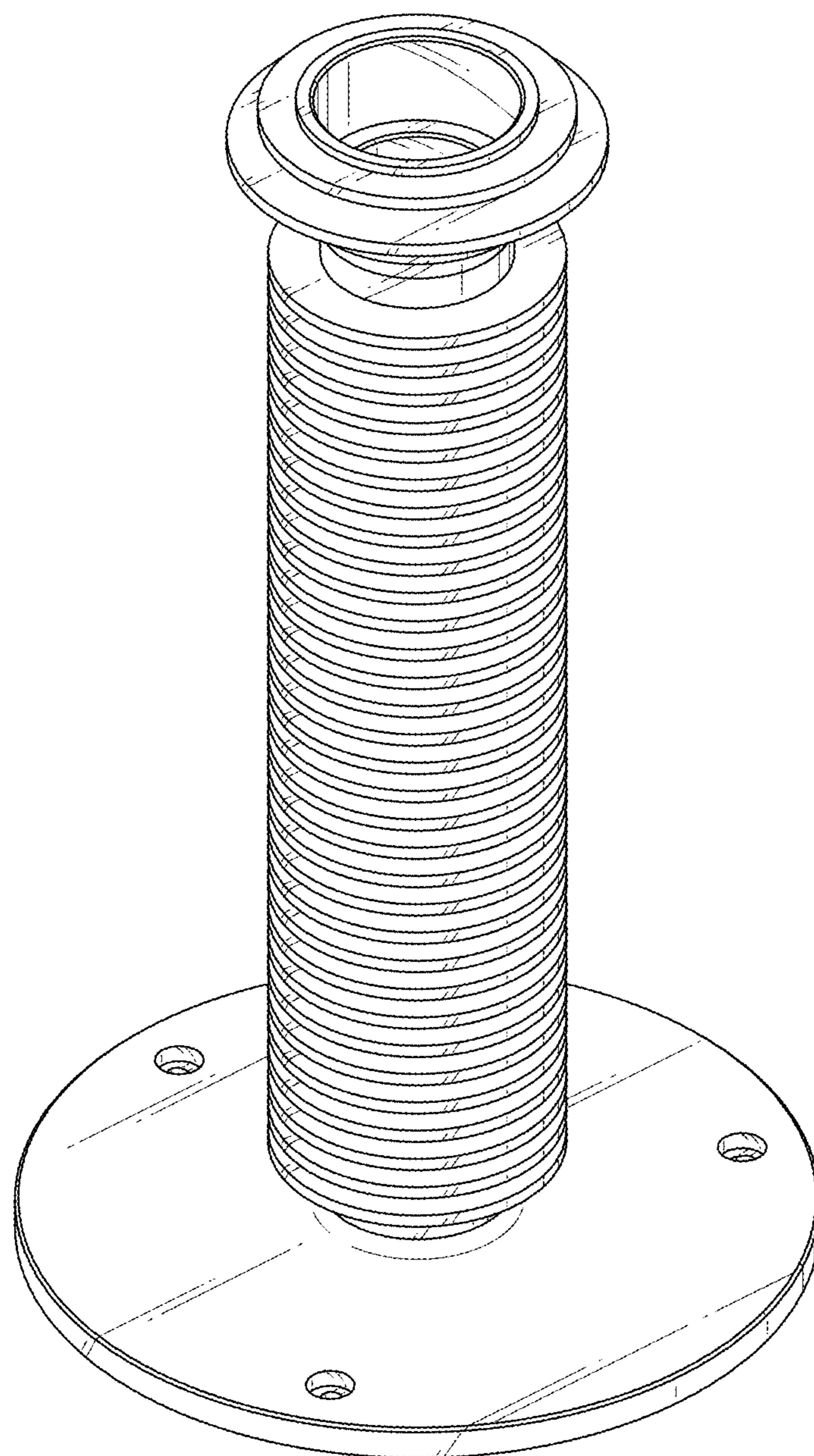


FIG. 1

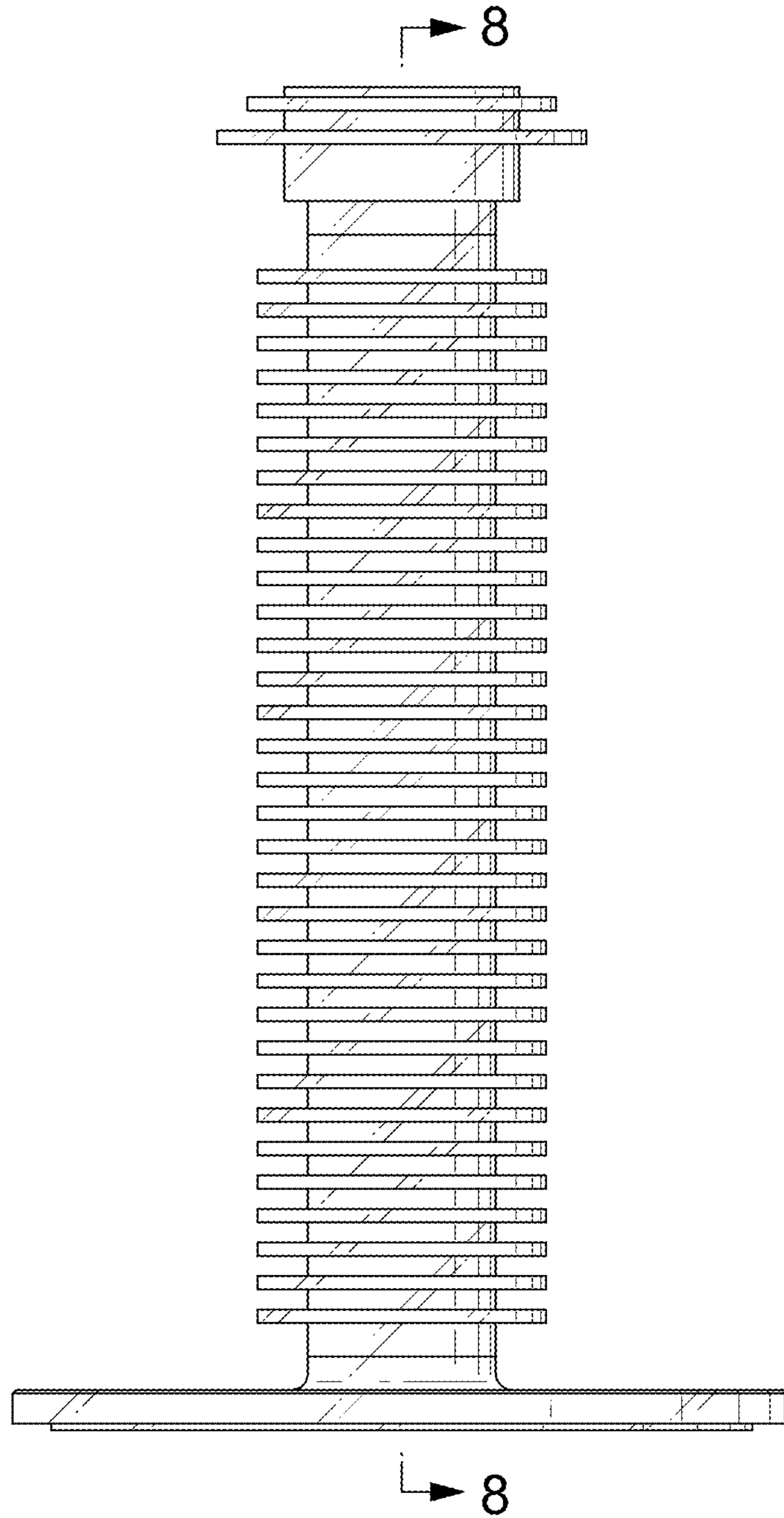


FIG. 2

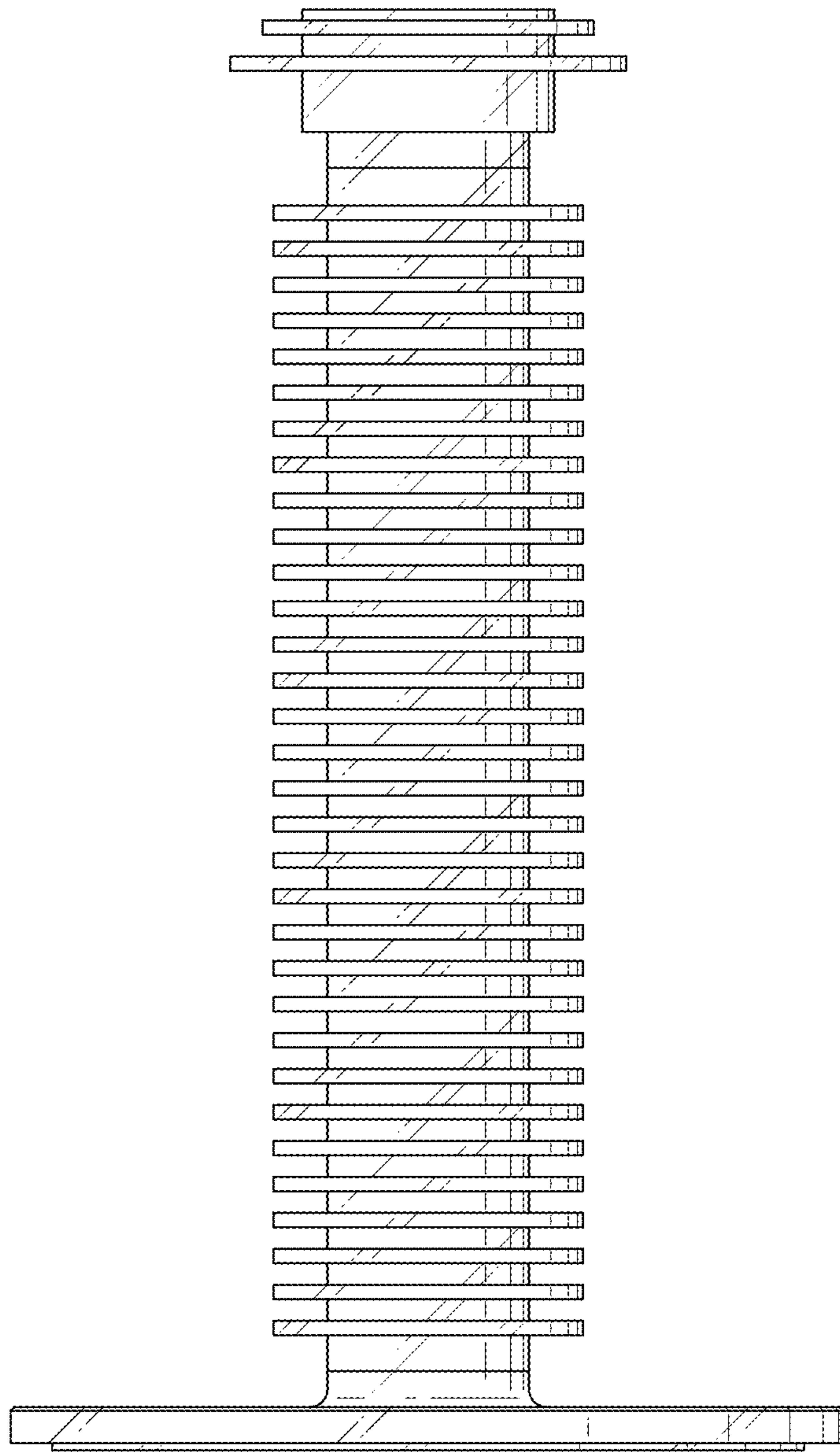


FIG. 3

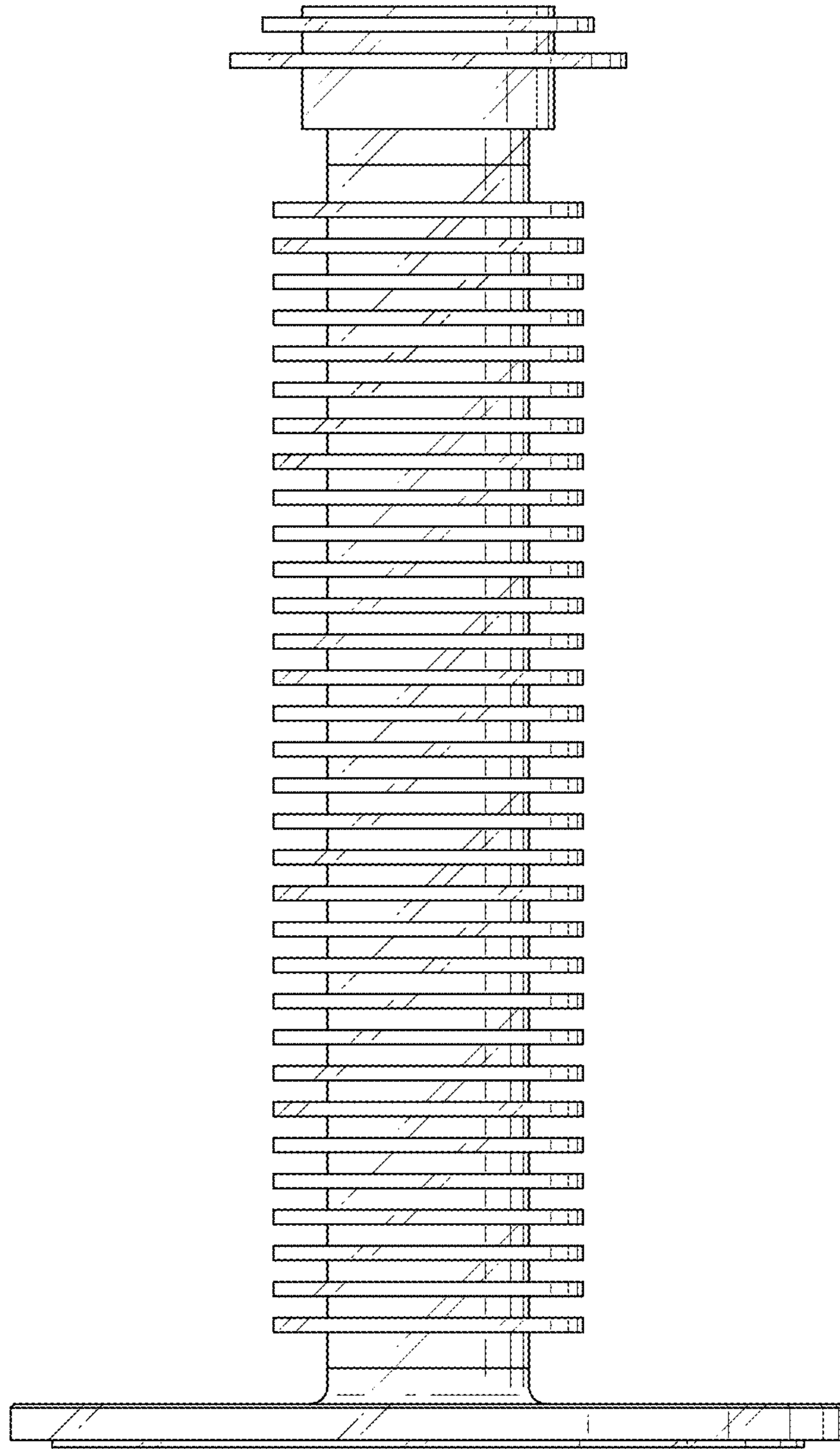


FIG. 4

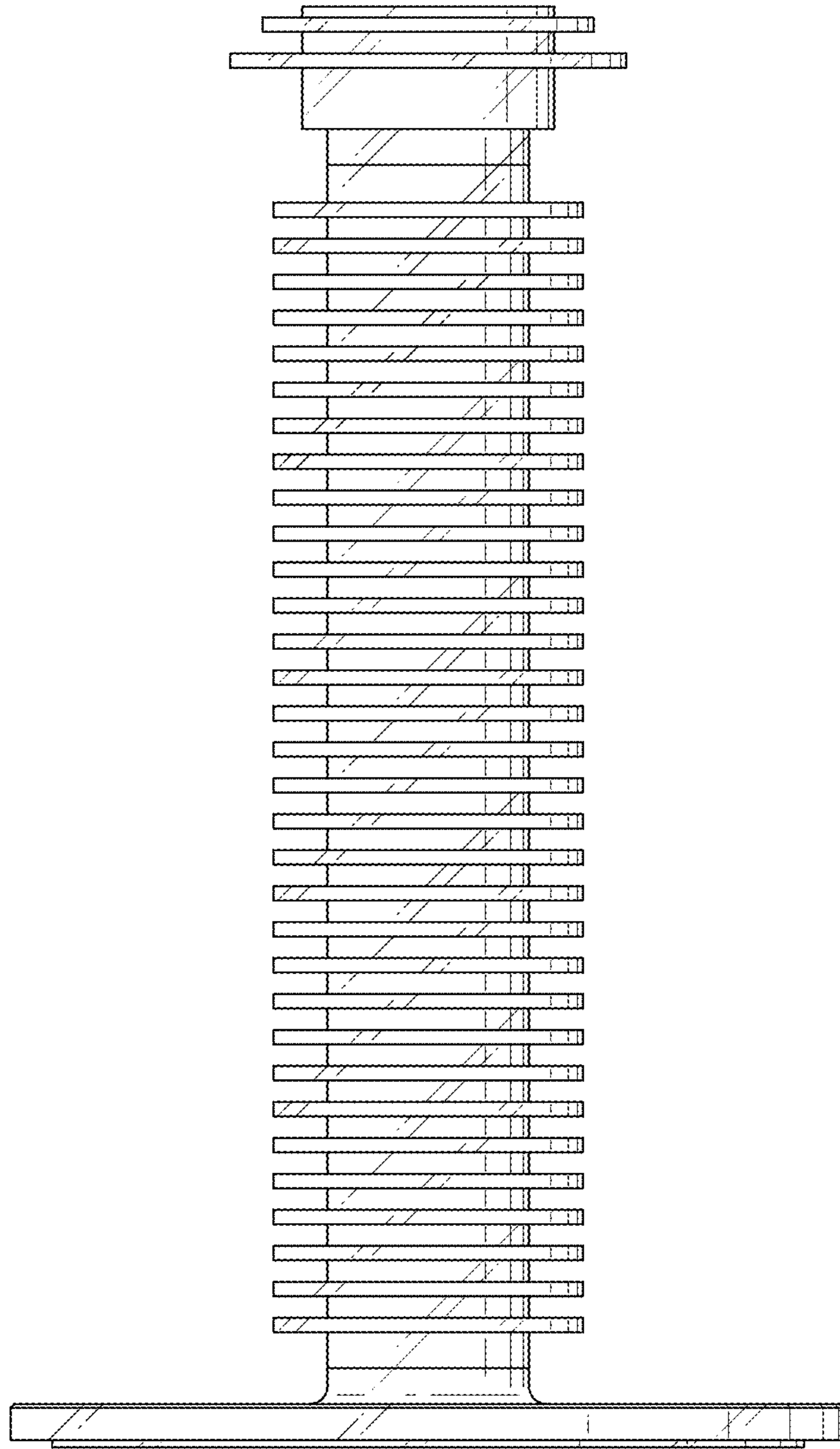


FIG. 5

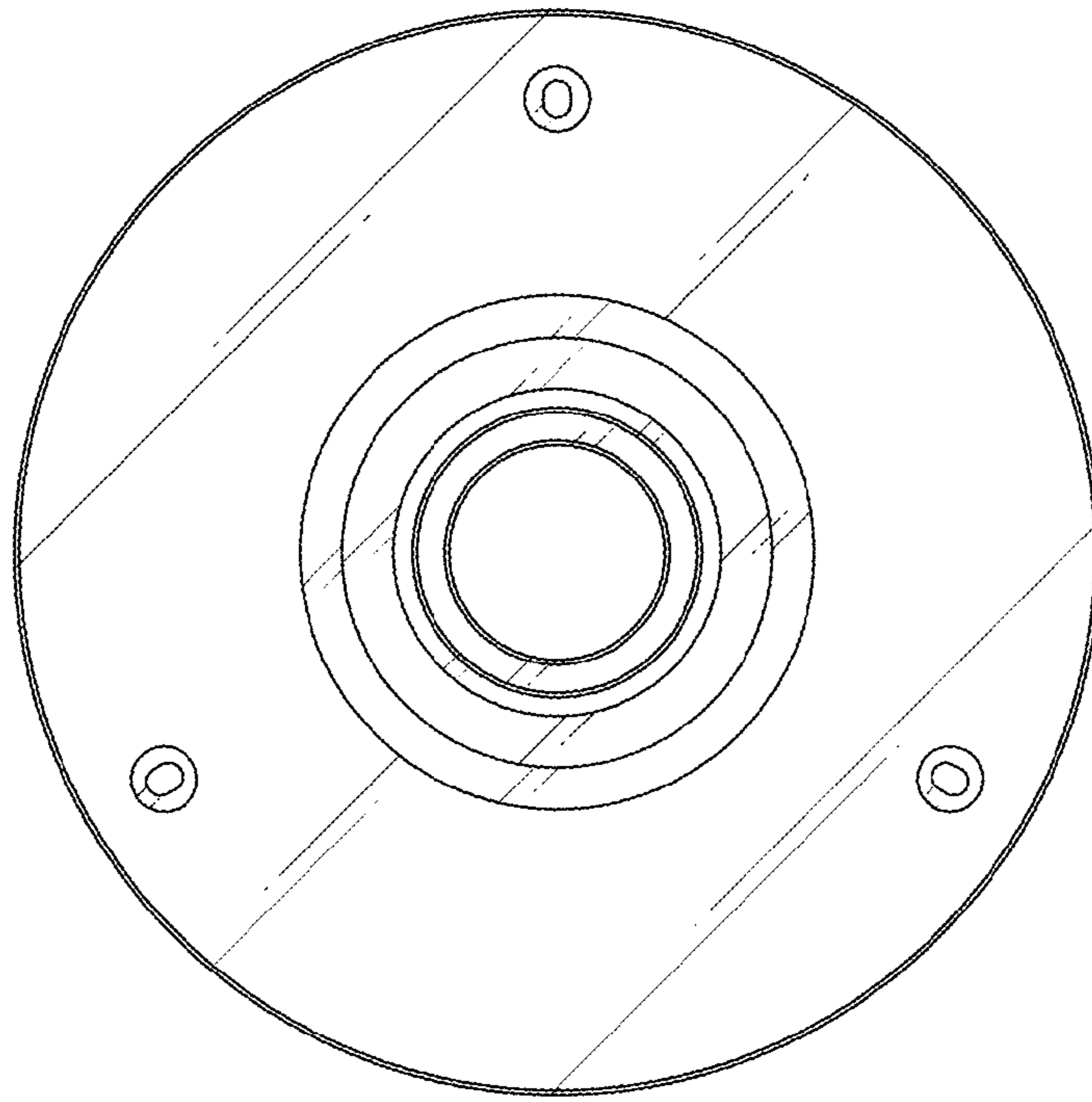


FIG. 6

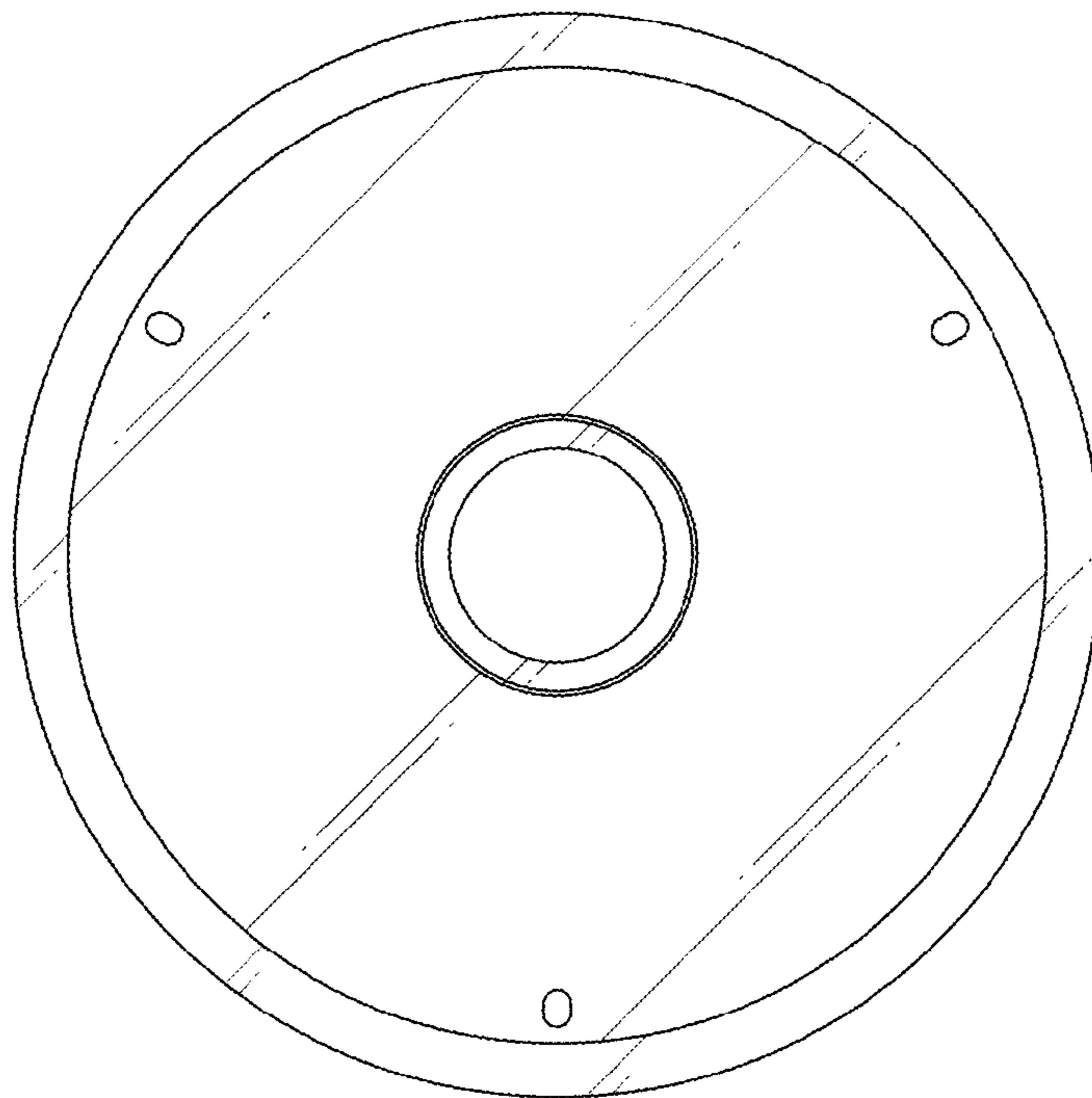


FIG. 7

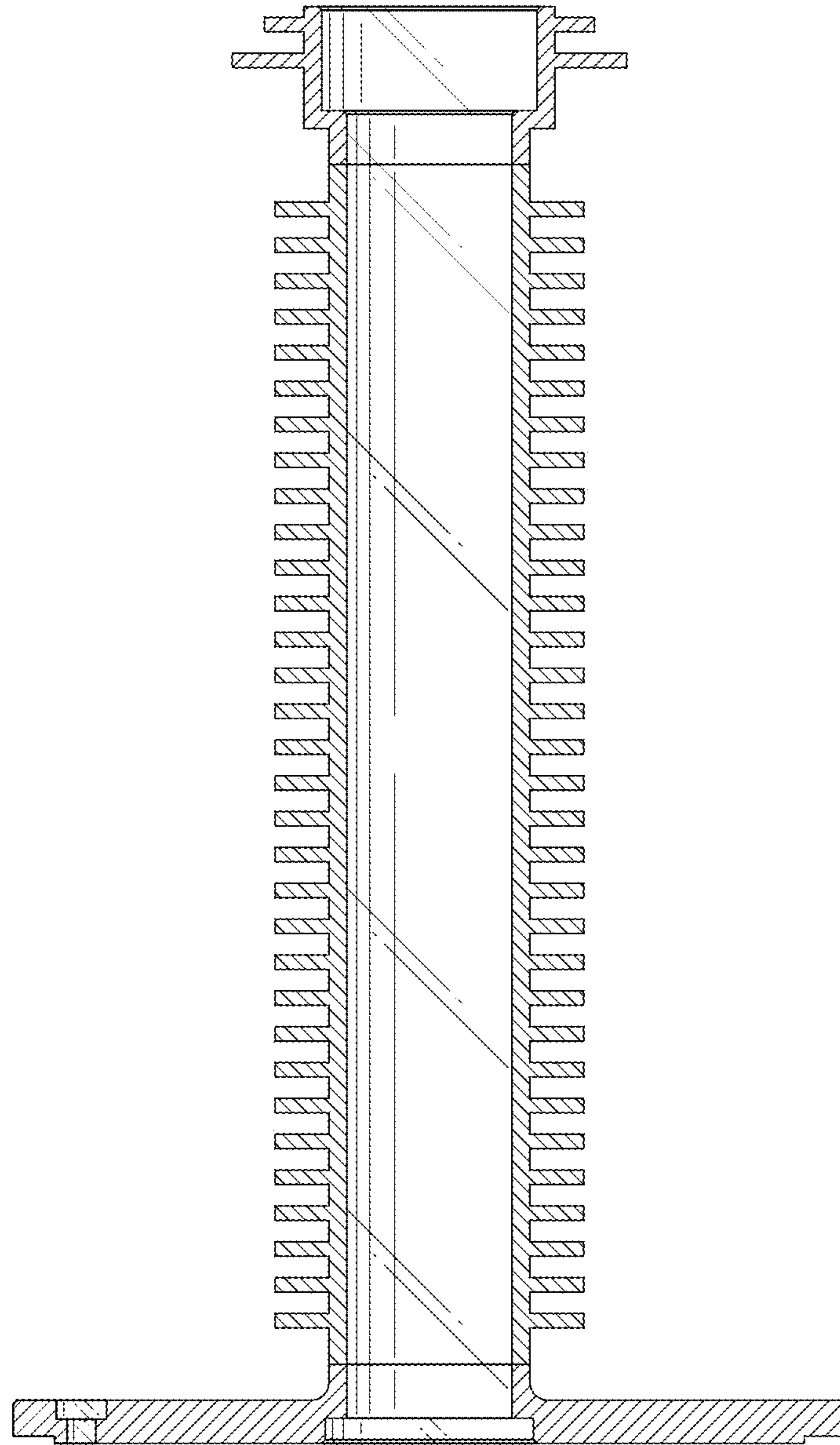


FIG. 8